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**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT****Complete if Known**

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				<b>Complete if Known</b>	
				Application Number	
				Filing Date	
				First Named Inventor	Yoshitaka Sugawara
				Art Unit	
				Examiner Name	
Sheet	1	of	1	Attorney Docket Number	3688KE-1

**U.S. PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number-kind Code <sup>2 (if known)</sup>	Publication Date MM-DD-YYYY	Name of Patentee of Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US-			
		US-			
		US-			
		US-			

**FOREIGN PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>3</sup>
		Country Code <sup>2</sup> ; Number <sup>2</sup> ; Kind Code <sup>3</sup> (if known)					
AS		JP	- 08-018030	01/19/1996	Fuji Electric Co., Ltd.		
↓		JP	- 09-148681	06/06/1997	Sumitomo Electric Ind. Ltd.		
		JP	- 10-022495	01/23/1998	Meidensha Corp.		
		JP	- 2001-217363	08/10/2001	Hitachi Ltd.		
		JP	- 2002-325355	11/08/2002	The Kansai Electric Power Co., Inc.		
		JP	- 2001-325427	11/08/2002	The Kansai Electric Power Co., Inc.		
↓							

**OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)**

Examiner Initials*	Cite No. <sup>1</sup>	
AS		"4H-SiC HIGH POWER SIJFET MODULE" by Sugawara et al., ISPSD 2003, April 14-17, Cambridge, UK, pp. 127-130.
↓		"Structure of Stacking Faults Formed During the Forward Bias of 4H-SiC p-i-n Diodes" by Twigg et al., Applied Physics Letters, Vol. 82, No. 15, 14 April 2003, pp. 2410-2412
		"Recent Progress in SiC Power Device Developments and Application Studies" by Sugawara, ISPSD, April 14-17, 2003, Cambridge, UK., pp. 10-18.
		"4H-SiC p-n Diodes and Gate Turnoff Thyristors for High-Power, High-Temperature Applications" by Agarwal et al., Pergamon, Solid State Electronics 44 (2000) pp. 303-308.

Examiner Signature	/A Sefer/	Date Considered	08/18/2006
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\*EXAMINER: Initial if reference is considered, whether or not citation is in conformance and not considered. Include copy of this form with next communication to applicant.